

Search Notes

Application/Control No.

10/000,232

Examiner

James Phan

Applicant(s)/Patent under
Reexamination

SCHARF ET AL.

Art Unit

2872

SEARCHED

Class	Subclass	Date	Examiner
359	205	8/05	J.P.
	208		
	212		
	223-		
	226		
	572		
	742		
438	29,32		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST. see attachment	8/05	J.P.